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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	1232
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	125
Number of Gates	8000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1280a-1pqqg160m

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2 – Detailed Specifications

Operating Conditions

Table 2-1 • Absolute Maximum Ratings¹

Symbol	Parameter	Limits	Units
VCC	DC supply voltage	–0.5 to +7.0	V
VI	Input voltage	–0.5 to VCC + 0.5	V
VO	Output voltage	–0.5 to VCC + 0.5	V
IIO	I/O source sink current ²	±20	mA
T _{STG}	Storage temperature	–65 to +150	°C

Notes:

1. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Device should not be operated outside the recommended operating conditions.
2. Device inputs are normally high impedance and draw extremely low current. However, when input voltage is greater than VCC + 0.5 V for less than GND –0.5 V, the internal protection diodes will be forward biased and can draw excessive current.

Table 2-2 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature range*	0 to +70	–40 to +85	–55 to +125	°C
Power supply tolerance	±5	±10	±10	%VCC

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Package Thermal Characteristics

The device junction to case thermal characteristic is θ_{jc} , and the junction to ambient air characteristic is θ_{ja} . The thermal characteristics for θ_{ja} are shown with two different air flow rates.

Maximum junction temperature is 150°C.

A sample calculation of the absolute maximum power dissipation allowed for a PQ160 package at commercial temperature and still air is as follows:

$$\frac{\text{Max. junction temp. } (\text{°C}) - \text{Max. ambient temp. } (\text{°C})}{\theta_{ja} \text{ °C/W}} = \frac{150 \text{ °C} - 70 \text{ °C}}{33 \text{ °C/W}} = 2.4 \text{ W}$$

EQ 1

Table 2-4 • Package Thermal Characteristics

Package Type*	Pin Count	θ_{jc}	θ_{ja} Still Air	θ_{ja} 300 ft./min.	Units
Ceramic Pin Grid Array	100	5	35	17	°C/W
	132	5	30	15	°C/W
	176	8	23	12	°C/W
Ceramic Quad Flatpack	172	8	25	15	°C/W
Plastic Quad Flatpack ¹	100	13	48	40	°C/W
	144	15	40	32	°C/W
	160	15	38	30	°C/W
Plastic Leaded Chip Carrier	84	12	37	28	°C/W
Very Thin Quad Flatpack	100	12	43	35	°C/W
Thin Quad Flatpack	176	15	32	25	°C/W

Notes: (Maximum Power in Still Air)

1. Maximum power dissipation values for PQFP packages are 1.9 W (PQ100), 2.3 W (PQ144), and 2.4 W (PQ160).
2. Maximum power dissipation for PLCC packages is 2.7 W.
3. Maximum power dissipation for VQFP packages is 2.3 W.
4. Maximum power dissipation for TQFP packages is 3.1 W.

Power Dissipation

$$P = [ICC_{\text{standby}} + ICC_{\text{active}}] * VCC + IOL * VOL * N + IOH * (VCC - VOH) * M$$

EQ 2

where:

ICC standby is the current flowing when no inputs or outputs are changing

ICCactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source currents.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M is the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the family type, design details, and on the system I/O. The power can be divided into two components: static and active.

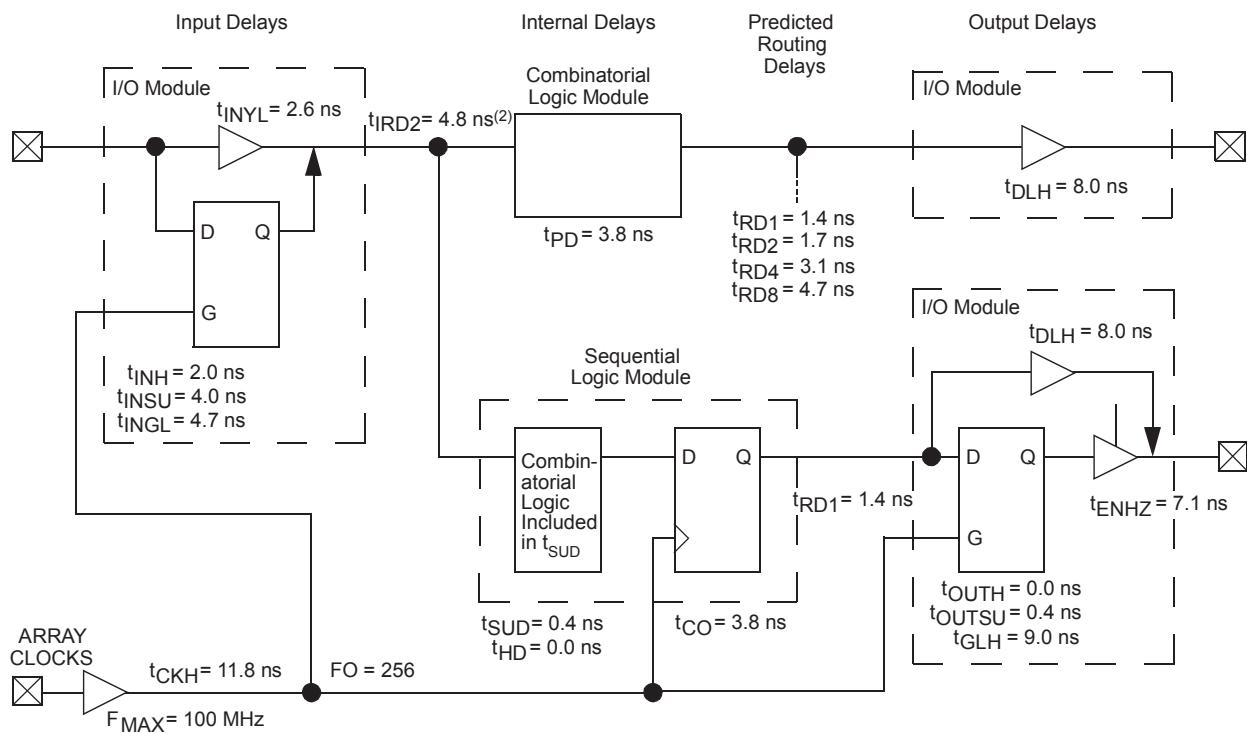
Determining Average Switching Frequency

To determine the switching frequency for a design, you must have a detailed understanding of the data input values to the circuit. The following guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are given in [Table 2-8](#).

Table 2-8 • Guidelines for Predicting Power Dissipation

Data	Value
Logic Modules (m)	80% of modules
Inputs switching (n)	# inputs/4
Outputs switching (p)	# output/4
First routed array clock loads (q1)	40% of sequential modules
Second routed array clock loads (q2)	40% of sequential modules
Load capacitance (C_L)	35 pF
Average logic module switching rate (f_m)	F/10
Average input switching rate (f_n)	F/5
Average output switching rate (f_p)	F/10
Average first routed array clock rate (f_{q1})	F
Average second routed array clock rate (f_{q2})	F/2

ACT 2 Timing Model¹



Notes:

- Values shown for A1240A-2 at worst-case commercial conditions.
- Input module predicted routing delay

Figure 2-1 • Timing Model

Timing Derating Factor (Temperature and Voltage)

Table 2-9 • Timing Derating Factor (Temperature and Voltage)

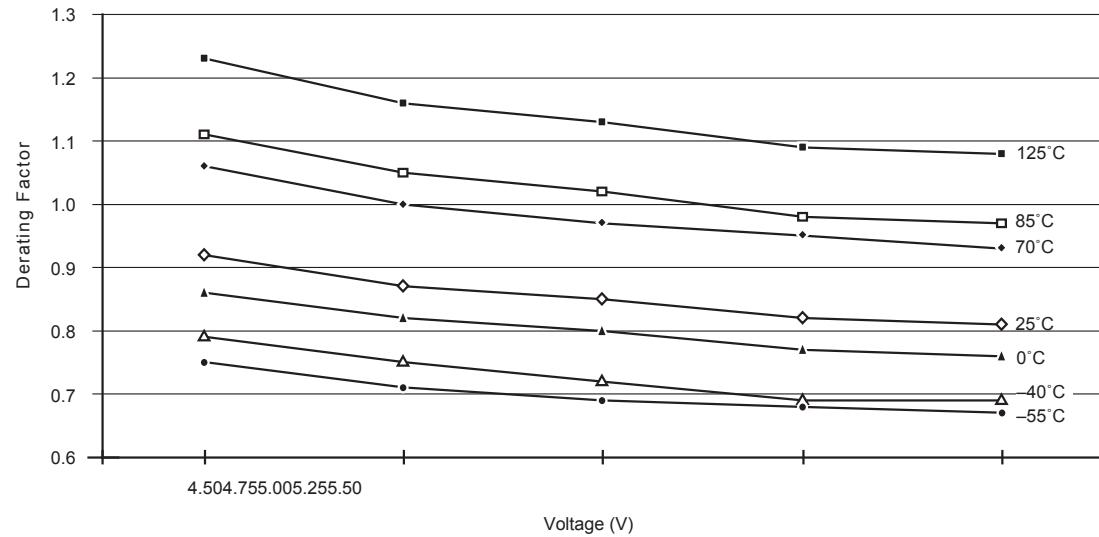
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.69	1.11	0.67	1.23

Table 2-10 • Timing Derating Factor for Designs at Typical Temperature ($T_J = 25^\circ\text{C}$) and Voltage (5.0 V)

(Commercial Maximum Specification) x	0.85
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**Table 2-11 • Temperature and Voltage Derating Factors
(normalized to Worst-Case Commercial, $T_J = 4.75 \text{ V}, 70^\circ\text{C}$)**

	-55	-40	0	25	70	85	125
4.50	0.75	0.79	0.86	0.92	1.06	1.11	1.23
4.75	0.71	0.75	0.82	0.87	1.00	1.05	1.13
5.00	0.69	0.72	0.80	0.85	0.97	1.02	1.13
5.25	0.68	0.69	0.77	0.82	0.95	0.98	1.09
5.50	0.67	0.69	0.76	0.81	0.93	0.97	1.08



Note: This derating factor applies to all routing and propagation delays.

**Figure 2-9 • Junction Temperature and Voltage Derating Curves
(normalized to Worst-Case Commercial, $T_J = 4.75 \text{ V}, 70^\circ\text{C}$)**

A1225A Timing Characteristics (continued)

Table 2-14 • A1225A Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C

TTL Output Module Timing ¹		-2 Speed		-1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{DLH}	Data to Pad High		8.0		9.0		10.6	ns
t _{DHL}	Data to Pad Low		10.1		11.4		13.4	ns
t _{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.6		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.3		9.5		11.1	ns
t _{GLH}	G to Pad High		8.9		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.07		0.08		0.09	ns/pF
d _{THL}	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing ¹								
t _{DLH}	Data to Pad High		10.1		11.5		13.5	ns
t _{DHL}	Data to Pad Low		8.4		9.6		11.2	ns
t _{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.6		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.3		9.5		11.1	ns
t _{GLH}	G to Pad High		8.9		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.12		0.13		0.16	ns/pF
d _{THL}	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. Delays based on 50 pF loading.
2. SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx.

A1240A Timing Characteristics

Table 2-15 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C

Logic Module Propagation Delays ¹		-2 Speed ³		-1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD1}	Single Module		3.8		4.3		5.0	ns
t _{CO}	Sequential Clock to Q		3.8		4.3		5.0	ns
t _{GO}	Latch G to Q		3.8		4.3		5.0	ns
t _{RS}	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted Routing Delays ²								
t _{RD1}	FO = 1 Routing Delay		1.4		1.5		1.8	ns
t _{RD2}	FO = 2 Routing Delay		1.7		2.0		2.3	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.6		3.0	ns
t _{RD4}	FO = 4 Routing Delay		3.1		3.5		4.1	ns
t _{RD8}	FO = 8 Routing Delay		4.7		5.4		6.3	ns
Sequential Timing Characteristics ^{3,4}								
t _{SUD}	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.5		6.0		6.5		ns
t _{WASYN}	Flip-Flop (Latch) Clock Asynchronous Pulse Width	4.5		6.0		6.5		ns
t _A	Flip-Flop Clock Input Period	9.8		12.0		15.0		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		100.0		80.0		66.0	MHz

Notes:

- For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$ —whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.
- Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

A1240A Timing Characteristics (continued)

Table 2-16 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays		-2 Speed		-1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{INYH}	Pad to Y High		2.9		3.3		3.8	ns
t _{INYL}	Pad to Y Low		2.6		3.0		3.5	ns
t _{INGH}	G to Y High		5.0		5.7		6.6	ns
t _{INGL}	G to Y Low		4.7		5.4		6.3	ns
Input Module Predicted Input Routing Delays*								
t _{IRD1}	FO = 1 Routing Delay		4.2		4.8		5.6	ns
t _{IRD2}	FO = 2 Routing Delay		4.8		5.4		6.4	ns
t _{IRD3}	FO = 3 Routing Delay		5.4		6.1		7.2	ns
t _{IRD4}	FO = 4 Routing Delay		5.9		6.7		7.9	ns
t _{IRD8}	FO = 8 Routing Delay		7.9		8.9		10.5	ns
Global Clock Network								
t _{CKH}	Input Low to High	FO = 32		10.2		11.0		12.8
		FO = 256		11.8		13.0		15.7
t _{CKL}	Input High to Low	FO = 32		10.2		11.0		12.8
		FO = 256		12.0		13.2		15.9
t _{PWH}	Minimum Pulse Width High	FO = 32	3.8		4.5		5.5	
		FO = 256	4.1		5.0		5.8	
t _{PWL}	Minimum Pulse Width Low	FO = 32	3.8		4.5		5.5	
		FO = 256	4.1		5.0		5.8	
t _{CKSW}	Maximum Skew	FO = 32	0.5		0.5		0.5	
		FO = 256	2.5		2.5		2.5	
t _{SUEXT}	Input Latch External Setup	FO = 32	0.0		0.0		0.0	
		FO = 256	0.0		0.0		0.0	
t _{HEXT}	Input Latch External Hold	FO = 32	7.0		7.0		7.0	
		FO = 256	11.2		11.2		11.2	
t _P	Minimum Period	FO = 32	8.1		9.1		11.1	
		FO = 256	8.8		10.0		11.7	
f _{MAX}	Maximum Frequency	FO = 32		125.0		110.0		90.0
		FO = 256		115.0		100.0		85.0

Note: *These parameters should be used for estimating device performance. Optimization techniques may further reduce delays by 0 to 4 ns. Routing delays are for typical designs across worst-case operating conditions. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1240A Timing Characteristics (continued)

Table 2-17 • A1240A Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C

TTL Output Module Timing ¹		-2 Speed		-1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{DLH}	Data to Pad High		8.0		9.0		10.6	ns
t _{DHL}	Data to Pad Low		10.1		11.4		13.4	ns
t _{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.7		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t _{GLH}	G to Pad High		9.0		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.07		0.08		0.09	ns/pF
d _{THL}	Delta High to Low		0.12		0.13		0.16	ns/pF
CMOS Output Module Timing ¹								
t _{DLH}	Data to Pad High		10.2		11.5		13.5	ns
t _{DHL}	Data to Pad Low		8.4		9.6		11.2	ns
t _{ENZH}	Enable Pad Z to High		8.9		10.0		11.8	ns
t _{ENZL}	Enable Pad Z to Low		11.7		13.2		15.5	ns
t _{ENHZ}	Enable Pad High to Z		7.1		8.0		9.4	ns
t _{ENLZ}	Enable Pad Low to Z		8.4		9.5		11.1	ns
t _{GLH}	G to Pad High		9.0		10.2		11.9	ns
t _{GHL}	G to Pad Low		11.2		12.7		14.9	ns
d _{TLH}	Delta Low to High		0.12		0.13		0.16	ns/pF
d _{THL}	Delta High to Low		0.09		0.10		0.12	ns/pF

Notes:

1. Delays based on 50 pF loading.
2. SSO information can be found at www.microsemi.com/soc/techdocs/appnotes/board_consideration.aspx.

A1280A Timing Characteristics

Table 2-18 • A1280A Worst-Case Commercial Conditions, VCC = 4.75 V, TJ = 70°C

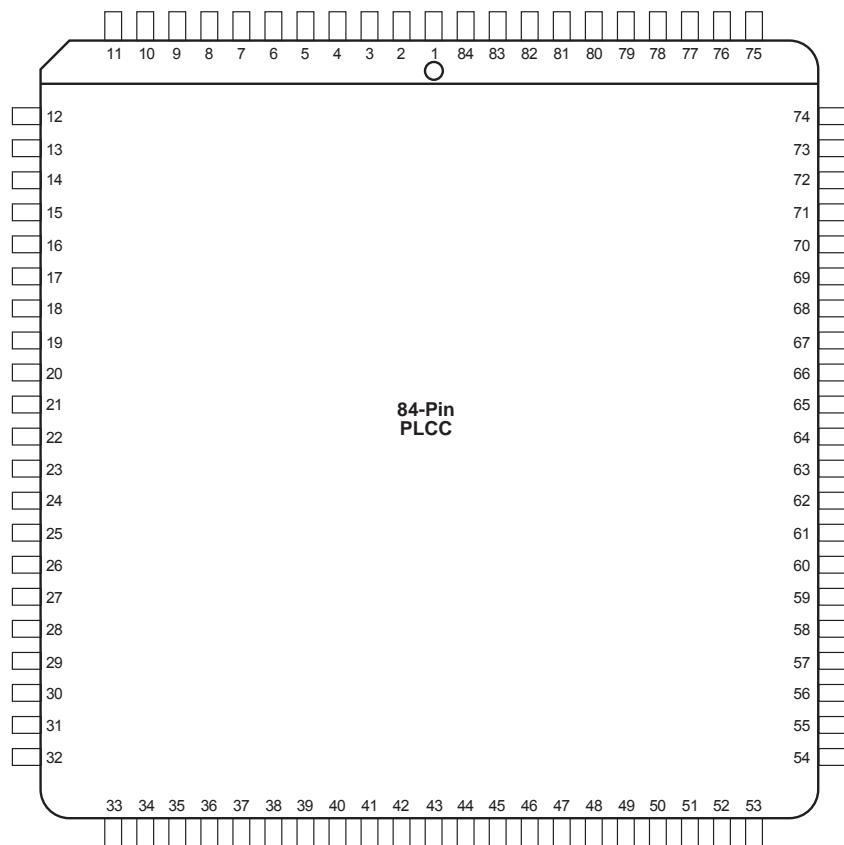
Logic Module Propagation Delays ¹		-2 Speed ³		-1 Speed		Std. Speed		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD1}	Single Module		3.8		4.3		5.0	ns
t _{CO}	Sequential Clock to Q		3.8		4.3		5.0	ns
t _{GO}	Latch G to Q		3.8		4.3		5.0	ns
t _{RS}	Flip-Flop (Latch) Reset to Q		3.8		4.3		5.0	ns
Predicted Routing Delays ²								
t _{RD1}	FO = 1 Routing Delay		1.7		2.0		2.3	ns
t _{RD2}	FO = 2 Routing Delay		2.5		2.8		3.3	ns
t _{RD3}	FO = 3 Routing Delay		3.0		3.4		4.0	ns
t _{RD4}	FO = 4 Routing Delay		3.7		4.2		4.9	ns
t _{RD8}	FO = 8 Routing Delay		6.7		7.5		8.8	ns
Sequential Timing Characteristics ^{3,4}								
t _{SUD}	Flip-Flop (Latch) Data Input Setup	0.4		0.4		0.5		ns
t _{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Setup	0.8		0.9		1.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	5.5		6.0		7.0		ns
t _{WASYN}	Flip-Flop (Latch) Clock Asynchronous Pulse Width	5.5		6.0		7.0		ns
t _A	Flip-Flop Clock Input Period	11.7		13.3		18.0		ns
t _{INH}	Input Buffer Latch Hold	0.0		0.0		0.0		ns
t _{INSU}	Input Buffer Latch Setup	0.4		0.4		0.5		ns
t _{OUTH}	Output Buffer Latch Hold	0.0		0.0		0.0		ns
t _{OUTSU}	Output Buffer Latch Setup	0.4		0.4		0.5		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency		85.0		75.0		50.0	MHz

Notes:

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$ —whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the DirectTime Analyzer utility.
4. Setup and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.

3 – Package Pin Assignments

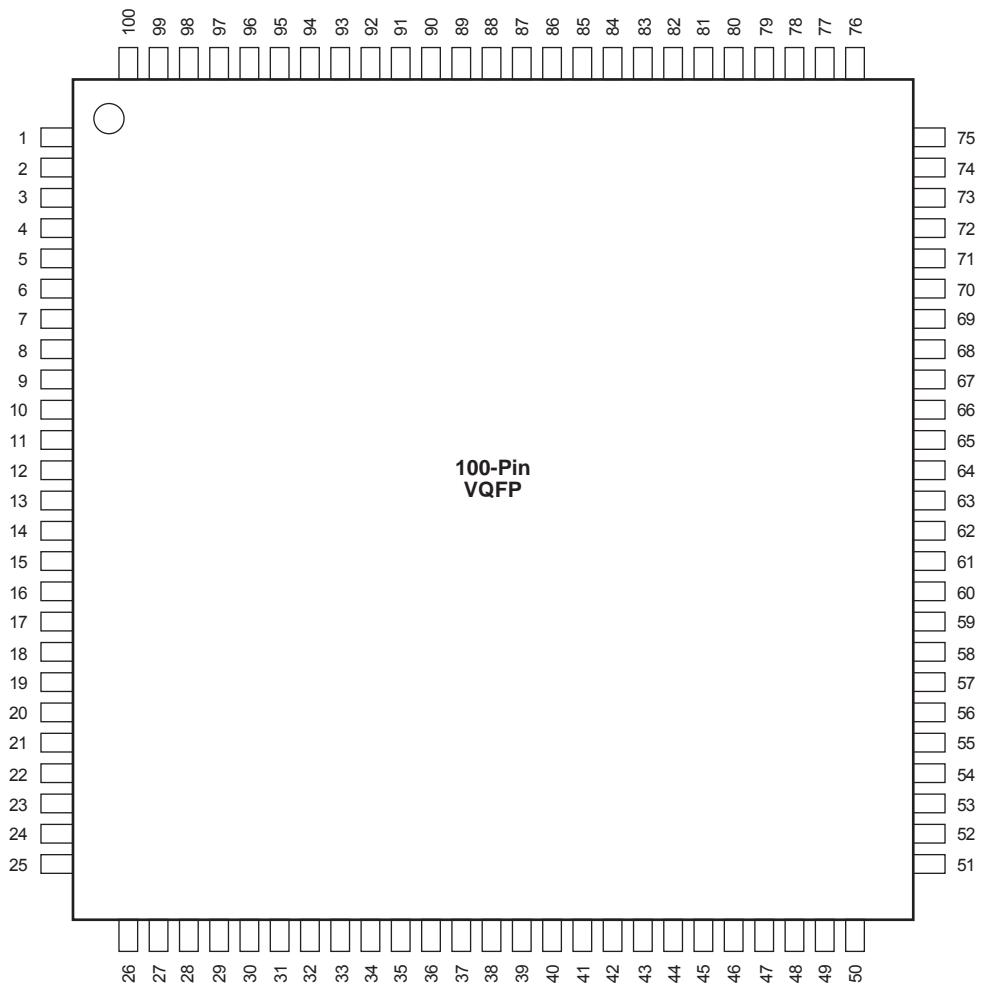
PL84



Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>.

VQ100



Note

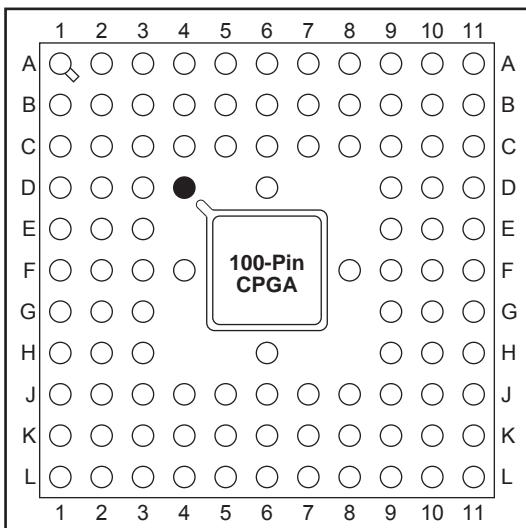
For Package Manufacturing and Environmental information, visit the Resource Center at
<http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

CQ172		CQ172	
Pin Number	A1280A Function	Pin Number	A1280A Function
1	MODE	107	VCC
7	GND	108	GND
12	VCC	109	VCC
17	GND	110	VCC
22	GND	113	VCC
23	VCC	118	GND
24	VCC	123	GND
27	VCC	131	SDI, I/O
32	GND	136	VCC
37	GND	141	GND
50	VCC	148	PRA, I/O
55	GND	150	CLKA, I/O
65	GND	151	VCC
66	VCC	152	GND
75	GND	154	CLKB, I/O
80	VCC	156	PRB, I/O
85	SDO	161	GND
98	GND	166	VCC
103	GND	171	DCLK, I/O
106	GND		

Notes:

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

PG100



● Orientation Pin

Note

For Package Manufacturing and Environmental information, visit the Resource Center at
<http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG132		PG132	
Pin Number	A1240A Function	Pin Number	A1240A Function
A1	MODE	G3	VCC
B5	GND	G4	VCC
B6	CLKB, I/O	G10	VCC
B7	CLKA, I/O	G11	VCC
B8	PRA, I/O	G12	VCC
B9	GND	G13	VCC
B12	SDI, I/O	H13	GND
C3	DCLK, I/O	J2	GND
C5	GND	J3	GND
C6	PRB, I/O	J11	GND
C7	VCC	K7	VCC
C9	GND	K12	GND
D7	VCC	L5	GND
E3	GND	L7	VCC
E11	GND	L9	GND
E12	GND	M9	GND
F4	GND	N12	SDO
G2	VCC		

Notes:

1. All unlisted pin numbers are user I/Os.
2. MODE pin should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

